

DATA SHEET

74F521 8-bit identity comparator

Product specification

1990 May 15

IC15 Data Handbook

8-bit identity comparator

74F521

FEATURES

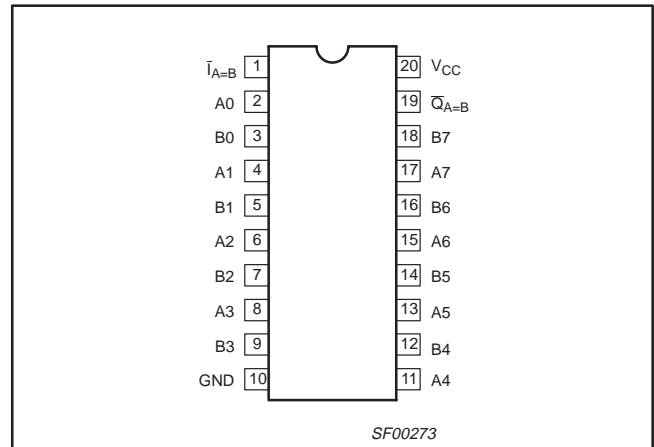
- Compares two 8-bit words in 6.5ns typical
- Expandable to any word length

DESCRIPTION

The 74F521 is an expandable 8-bit comparator. It compares two words of up to 8 bits each and provides a Low output when the two words match bit for bit. The expansion input $\bar{I}_{A=B}$ also serves as an active-Low enable input.

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F521	7.0ns	24mA

PIN CONFIGURATION



ORDERING INFORMATION

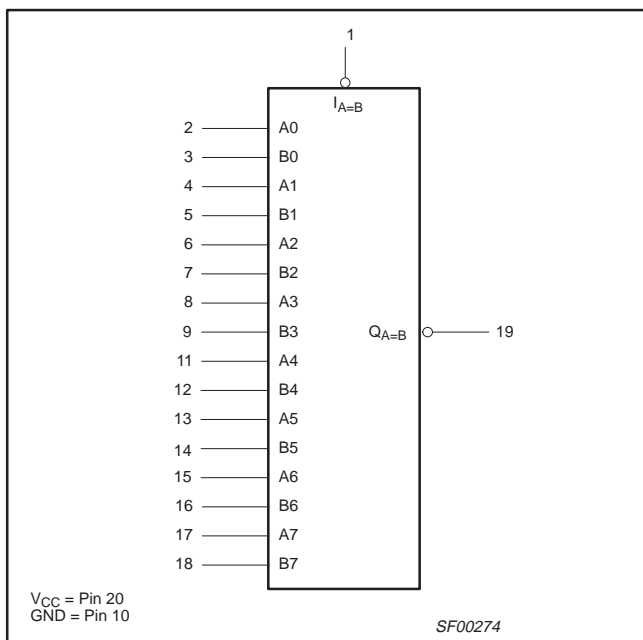
DESCRIPTION	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$, $T_{amb} = 0^{\circ}C$ to $+70^{\circ}C$	PKG DWG #
20-pin plastic DIP	N74F521N	SOT146-1
20-pin plastic SOL	N74F521D	SOT163-1

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

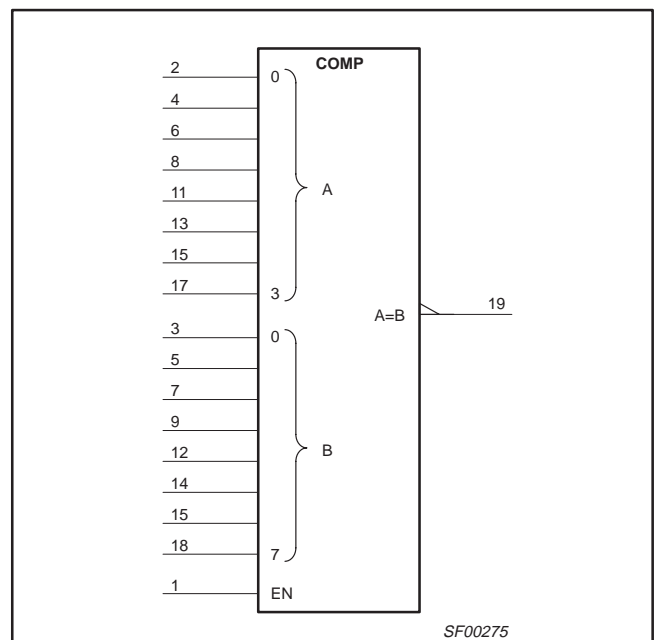
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A0 – A7	Word A inputs	1.0/1.0	20 μ A/0.6mA
B0 – B7	Word B inputs	1.0/1.0	20 μ A/0.6mA
$\bar{I}_{A=B}$	Expansion or Enable input (active Low)	1.0/1.0	20 μ A/0.6mA
$\bar{Q}_{A=B}$	Identity output (active Low)	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20 μ A in the High state and 0.6mA in the Low state.

LOGIC SYMBOL



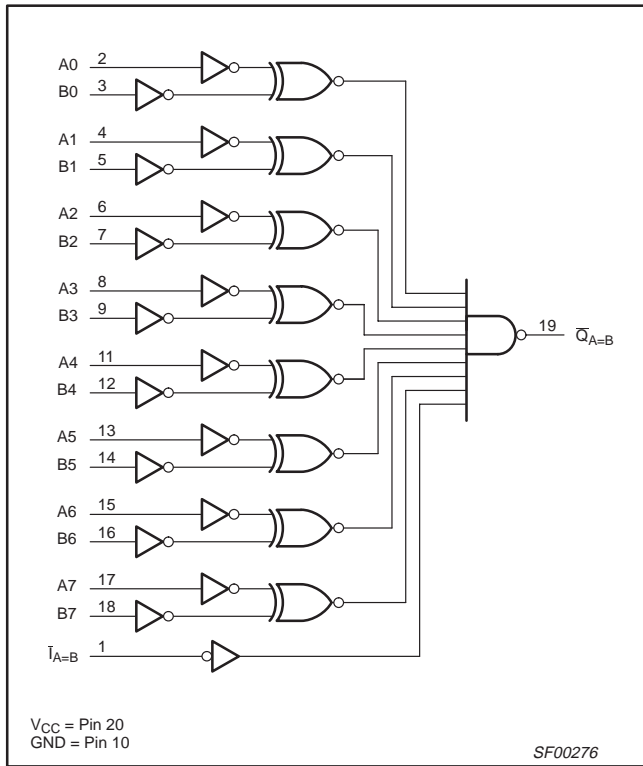
IEC/IEEE SYMBOL



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LOGIC DIAGRAM

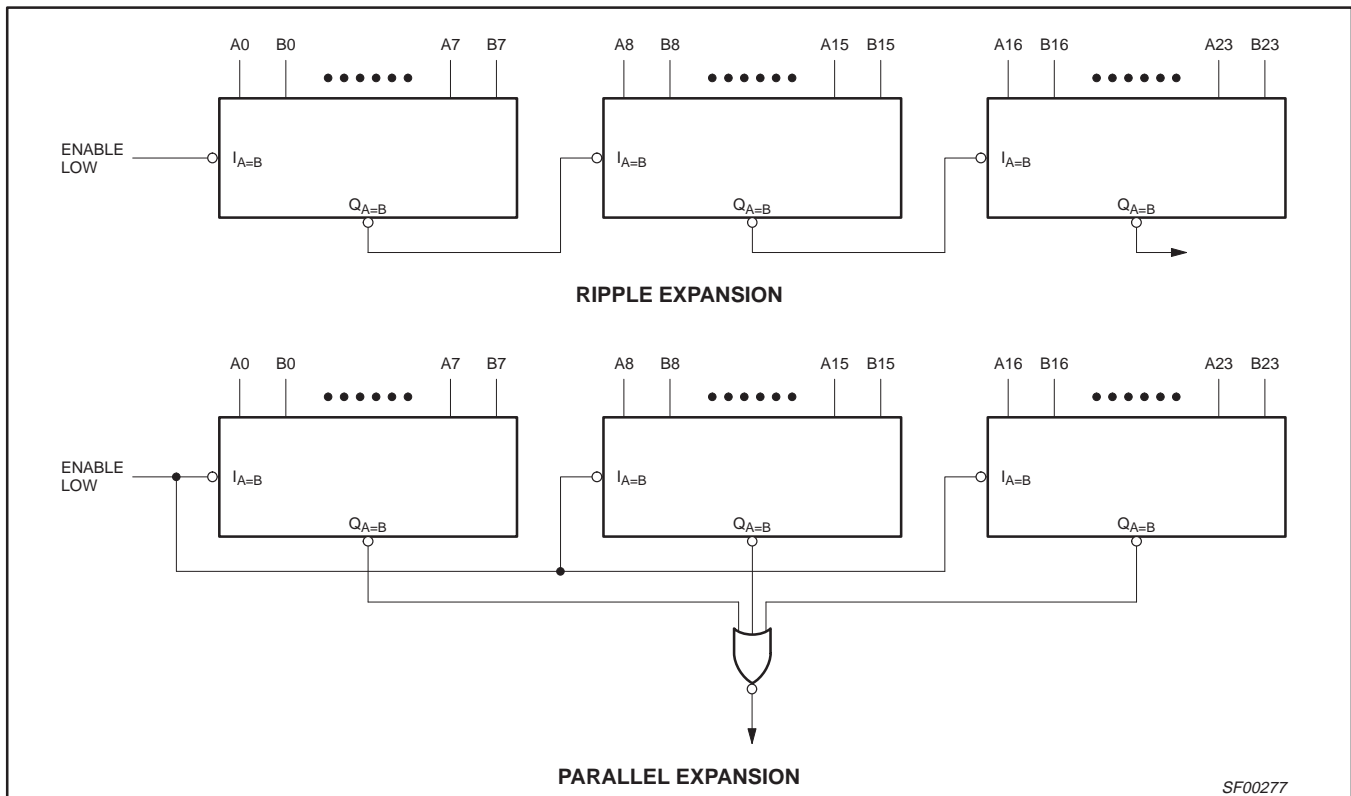


FUNCTION TABLE

INPUTS		OUTPUT
$\bar{I}_{A=B}$	A, B	$\bar{Q}_{A=B}$
L	A=B*	L
L	A≠B	H
H	A=B*	H
H	A≠B	H

H = High voltage level
L = Low voltage level
X = Don't care
* A0=B0, A1=B1, A2=B2, etc.

APPLICATIONS



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ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device.
Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	-0.5 to V _{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _{amb}	Operating free-air temperature range	0 to +70	°C
T _{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-1	mA
I _{OL}	Low-level output current			20	mA
T _{amb}	Operating free-air temperature range	0		+70	°C

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹	LIMITS			UNIT	
			MIN	TYP ²	MAX		
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IL} = MAX	±10%V _{CC}	2.5		V	
		V _{IH} = MIN, I _{OH} = MAX	±5%V _{CC}	2.7	3.4		
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IL} = MAX	±10%V _{CC}		0.30	V	
		V _{IH} = MIN, I _{OL} = MAX	±5%V _{CC}		0.30		
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I = I _{IK}		-0.73	-1.2	V	
I _I	Input current at maximum input voltage	V _{CC} = MAX, V _I = 7.0V			100	μA	
I _{IH}	High-level input current	V _{CC} = MAX, V _I = 2.7V			20	μA	
I _{IL}	Low-level input current	V _{CC} = MAX, V _I = 0.5V			-0.6	mA	
I _{OS}	Short-circuit output current ³	V _{CC} = MAX		-60	-150	mA	
I _{CC}	Supply current (total)	I _{CCH}	V _{CC} = MAX		24	36	mA
		I _{CCL}			24	36	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
- Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

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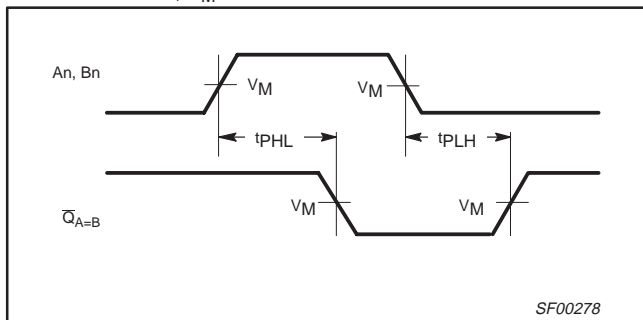
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AC ELECTRICAL CHARACTERISTICS

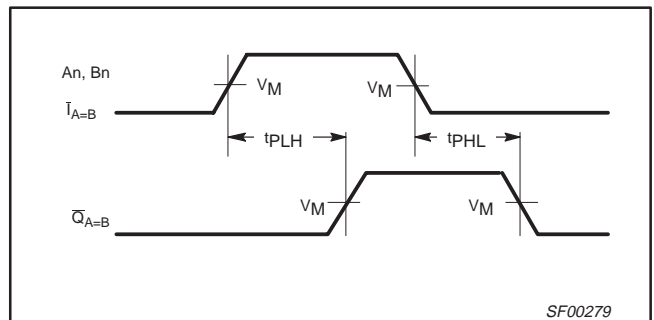
SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			V _{CC} = +5.0V T _{amb} = +25°C C _L = 50pF, R _L = 500Ω			V _{CC} = +5.0V ± 10% T _{amb} = 0°C to +70°C C _L = 50pF, R _L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay An or Bn to Q _{A=B}	Waveform 1, 2	3.5 3.0	8.0 8.0	9.5 9.0	3.5 2.5	11.0 10.5	ns
t _{PLH} t _{PHL}	Propagation delay I _{A=B} to Q _{A=B}	Waveform 2	3.0 3.5	5.0 6.5	6.5 7.0	3.0 3.5	7.5 8.0	ns

AC WAVEFORMS

For all waveforms, V_M = 1.5V.



Waveform 1. For Inverting Outputs



Waveform 2. For Non-Inverting Outputs

TEST CIRCUIT AND WAVEFORMS

Test Circuit for Totem-Pole Outputs

Input Pulse Definition

DEFINITIONS:
 R_L = Load resistor; see AC ELECTRICAL CHARACTERISTICS for value.
 C_L = Load capacitance includes jig and probe capacitance; see AC ELECTRICAL CHARACTERISTICS for value.
 R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

family	INPUT PULSE REQUIREMENTS					
	amplitude	V _M	rep. rate	t _w	t _{TLH}	t _{THL}
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns

SF00006

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DIP20: plastic dual in-line package; 20 leads (300 mil)

SOT146-1




DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	c	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	M _E	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	0.36 0.23	26.92 26.54	6.40 6.22	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.0
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.014 0.009	1.060 1.045	0.25 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.078

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT146-1			SC603			92-11-17 95-05-24

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SO20: plastic small outline package; 20 leads; body width 7.5 mm

SOT163-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁	A ₂	A ₃	b _p	c	D ⁽¹⁾	E ⁽¹⁾	e	H _E	L	L _p	Q	v	w	y	z ⁽¹⁾	θ
mm	2.65	0.30 0.10	2.45 2.25	0.25	0.49 0.36	0.32 0.23	13.0 12.6	7.6 7.4	1.27	10.65 10.00	1.4	1.1 0.4	1.1 1.0	0.25	0.25	0.1	0.9 0.4	8° 0°
inches	0.10	0.012 0.004	0.096 0.089	0.01	0.019 0.014	0.013 0.009	0.51 0.49	0.30 0.29	0.050	0.419 0.394	0.055	0.043 0.016	0.043 0.039	0.01	0.01	0.004	0.035 0.016	

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT163-1	075E04	MS-013AC				95-01-24 97-05-22

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Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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